U.S. Patent Application
Attorney Docket No. 02008.071002

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant :	Masahiro ISHIDA et al.	Art Unit :
Serial No.:		Examiner :
Filed :	Herewith	
Title :	METHOD AND APPARATUS FOR DEFECT ANALYSIS OF SEMI-CONDUCTOR INTEGRATED CIRCUIT	

Assistant Commissioner for Patents
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PRELIMINARY AMENDMENT

Prior to consideration on the merits, please amend the application as follows and consider the included remarks.